

Philips Semiconductors-Signetics

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Status	Product Specification
FAST Products	

FAST 74F280A, 74F280B

Parity Checker Generator

FEATURES

- High impedance NPN base inputs for reduced loading (20µA in Low and High states)
- Buffered inputs—one normalized load
- Word length easily expanded by cascading
- Industrial temperature range available (-40°C to +85°C) for 74F280B

9-Bit Odd/Even Parity Generator/Checker

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F280A	6.5ns	26mA
74F280B	5.5ns	26mA

DESCRIPTION

The 74F280A is a 9-bit Parity Generator or Checker commonly used to detect errors in high speed data transmission or data retrieval systems. Both Even (Σ_E) and Odd (Σ_O) parity outputs are available for generating and checking even or odd parity on up to 9 bits.

The Even (Σ_E) parity output is High when an even number of data inputs (I_0-I_8) are High. The Odd (Σ_O) parity output is High when an odd number of data inputs are High.

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ $T_A = 0^\circ C$ to $+70^\circ C$	INDUSTRIAL RANGE $V_{CC} = 5V \pm 10\%$ $T_A = -40^\circ C$ to $+85^\circ C$
14-Pin Plastic DIP	N74F280AN, N74F280BN	174F280BN
14-Pin Plastic SO	N74F280AD, N74F280BD	174F280BD

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
I_0-I_8	Data inputs	1.0/0.033	20µA/20µA
Σ_E, Σ_O	Parity outputs	50/33	1.0mA/20mA

NOTE:

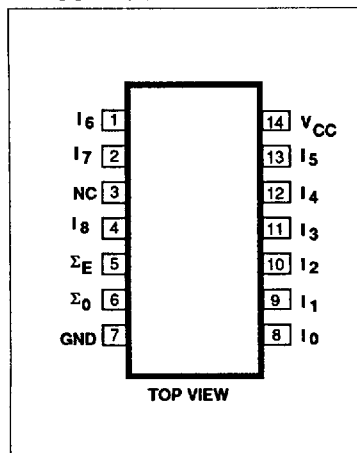
One (1.0) FAST Unit Load is defined as: 20µA in the High state and 0.6mA in the Low state.

Expansion to larger word sizes is accomplished by tying the Even (Σ_E) outputs of up to nine parallel devices to the data inputs of the

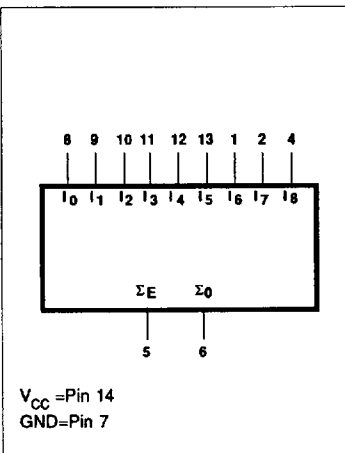
final stage. This expansion scheme allows an 81-bit data word to be checked in less than 20 ns.

The 74F280B is a faster version of 74F280A

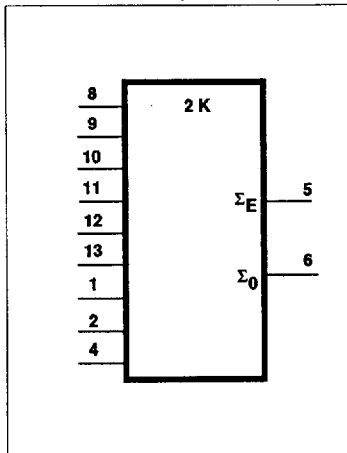
PIN CONFIGURATION



LOGIC SYMBOL



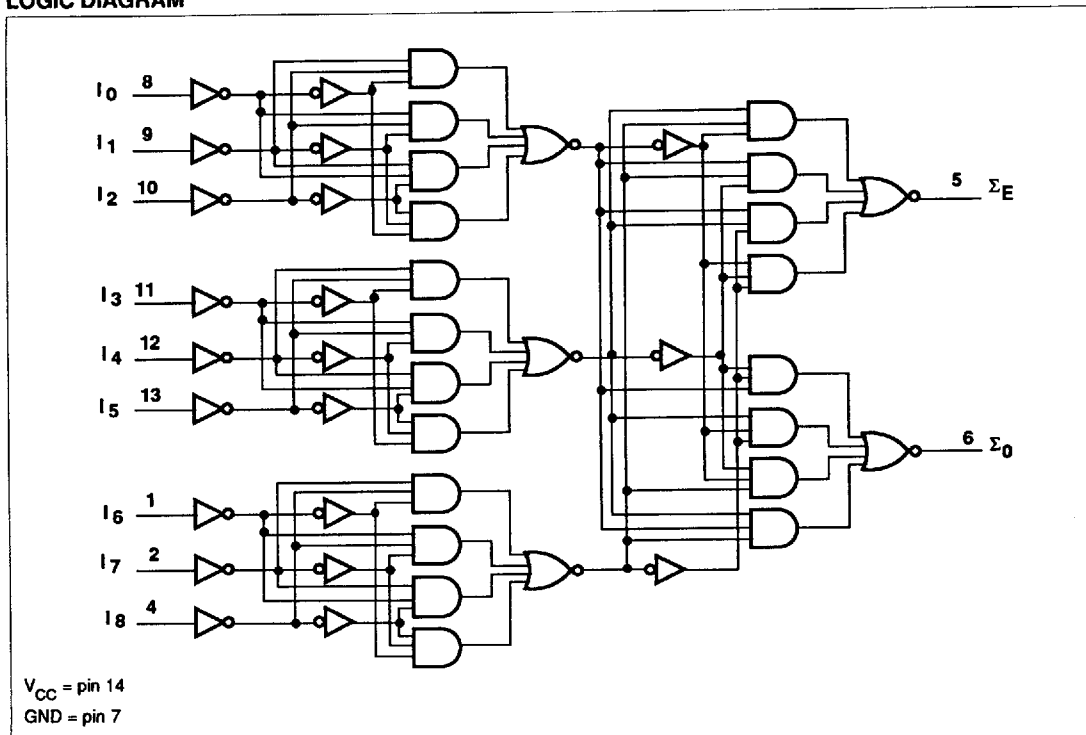
LOGIC SYMBOL (IEEE/IEC)



Parity Generator Checker

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LOGIC DIAGRAM



FUNCTION TABLE

INPUTS	OUTPUTS	
	Σ_E	Σ_O
Number of High data inputs (I_0-I_8)	Σ_E	Σ_O
Even — 0, 2, 4, 6, 8	H	L
Odd — 1, 3, 5, 7, 9	L	H

H = High voltage level

L = Low voltage level

ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to + V_{CC}	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_A	Operating free-air temperature range	Commercial range	0 to +70
		Industrial range	-40 to +85
T_{STG}	Storage temperature	-65 to +150	°C

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_H	High-level input voltage	2.0			V
V_L	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	Commercial range	0	70	°C
		Industrial range	-40	85	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT	
			Min	Typ ²	Max		
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$	2.5		V	
		$V_{IH} = \text{MIN}, I_{OH} = \text{MAX}$	$\pm 5\%V_{CC}$	2.7	3.4	V	
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.35	0.50	V
		Input clamp voltage	$V_{IH} = \text{MIN}, I_{OL} = \text{MAX}$	$\pm 5\%V_{CC}$		0.35	0.50
V_{IK}	Input current at maximum input voltage	$V_{CC} = \text{MIN}, I_1 = I_{IK}$			-0.73	-1.2	V
I_I		$V_{CC} = 0.0V, V_I = 7.0V$				100	μA
I_{IH}	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7V$				20	μA
	Low-level input current					40	μA
I_{IL}	Short-circuit output current ³	$V_{CC} = \text{MAX}, V_I = 0.5V$				-20	μA
I_{OS}	Supply current (total)	$V_{CC} = \text{MAX}$		-60		-150	mA
I_{CC}		$V_{CC} = \text{MAX}$			26	35	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5V, T_A = 25^\circ C$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

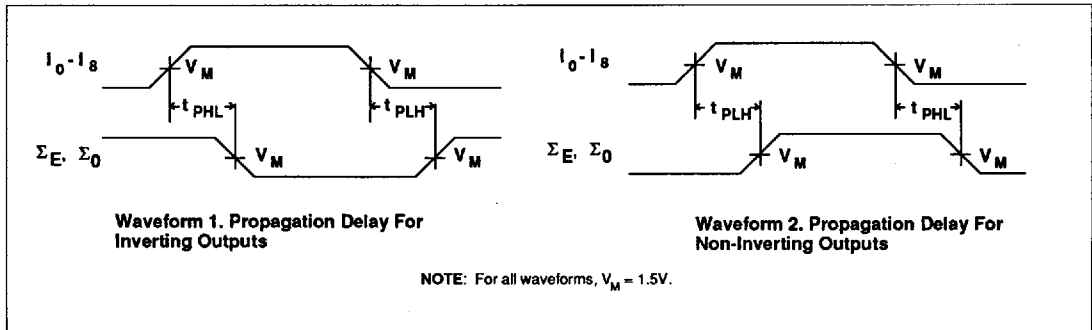
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT	
			$T_A = +25^\circ\text{C}$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$		
			Min	Typ	Max	Min	Max	Min		Max
t_{PLH} t_{PHL}	Propagation delay $I_0 - I_8 \text{ to } \Sigma_E$	'F280A Waveform 1,2	5.0	7.0	9.0	5.0	10.0			ns
			7.5	10.0	13.0	7.5	14.5			
t_{PLH} t_{PHL}	Propagation delay $I_0 - I_8 \text{ to } \Sigma_O$	Waveform 1,2	6.5	8.6	10.5	6.5	11.0			ns
			7.0	9.1	12.0	6.0	13.0			
t_{PLH} t_{PHL}	Propagation delay $I_0 - I_8 \text{ to } \Sigma_E$	'F280B Waveform 1,2	4.0	6.5	9.0	3.5	10.0	3.0	11.0	ns
			4.0	7.0	10.0	3.5	11.1	3.5	12.0	
t_{PLH} t_{PHL}	Propagation delay $I_0 - I_8 \text{ to } \Sigma_O$	Waveform 1,2	4.0	6.5	9.0	3.5	10.0	3.0	11.0	ns
			4.0	7.0	10.0	3.5	11.0	3.5	12.0	

AC WAVEFORMS



TEST CIRCUIT AND WAVEFORMS

